

| Form PTO 1449 (Modified) | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. 8733.20069 | | SERIAL NO. 09/446,330 | |
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| | | FILING DATE March 23, 2000 | | GROUP TBA | | | |
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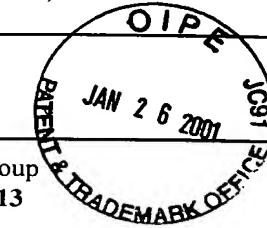
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Sergey E. Yakovenko, et al.Filing Date
March 23, 2000Group
2713

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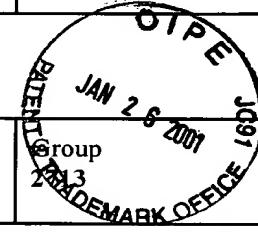
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